

**DEVICE
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DEI1070, DEI1071, DEI1072 ARINC 429 LINE DRIVER WITH RATE SELECT

FEATURES

- TTL/CMOS TO ARINC 429 Line Driver.
- Rate control input set Hi (100KBS) or Lo (12.5KBS) speed slew rates.
- Operates from $\pm 9.5V$ to $\pm 16.5V$ power supply.
- Drives full ARINC load.
- Output resistor options: 0, 10 or 37.5 Ohms.
- Packages: thermally enhanced 8 lead SOIC and ceramic sidebraced DIP
- Outputs Short Circuit Tolerant

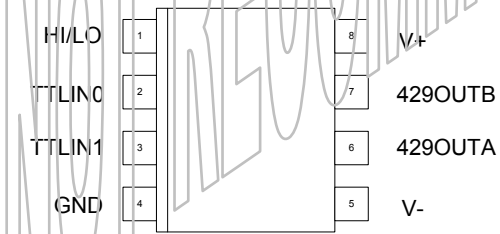
GENERAL DESCRIPTION

The DEI1070 family of 8 pin BiCMOS integrated circuits are line drivers designed to directly drive the ARINC 429 avionics serial digital data bus. The device converts TTL/CMOS serial input data to the tri-level RZ bipolar differential modulation format of the ARINC bus. A TTL/CMOS control input selects the output slew rate for HI (100KBS) and LOW (12.5KBS) speed operation. No external timing capacitors are required.

The DEI1070 has internal 37.5 Ohm output resistors, the DEI1071 has 10 Ohm resistors, and the DEI1072 has none. The 10 and 0 Ohm options require external series resistors which are typically used to implement a transient voltage protection network.

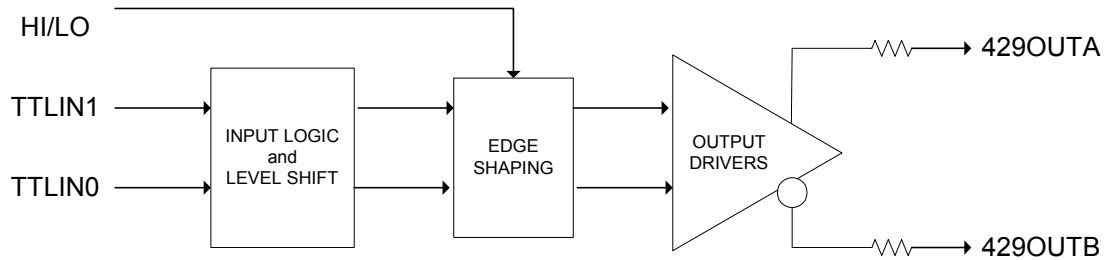
Table 1 PIN DESCRIPTION

PIN	NAME	DESCRIPTION
1	HI/LO	LOGIC INPUT. Slew rate control. 1 = Hi speed. 0 = Low speed.
2	TTLIN0	LOGIC INPUT. Serial digital data input 0.
3	TTLIN1	LOGIC INPUT. Serial digital data input 1.
4	GND	POWER INPUT. Ground.
5	V-	POWER INPUT. -9.5 to -16.5 VDC
6	429OUTA	429 OUTPUT. ARINC 429 format serial digital data output A.
7	429OUTB	429 OUTPUT. ARINC 429 format serial digital data output B.
8	V+	POWER INPUT. +9.5 to +16.5 VDC.



Note:
Heatsink pad is electrically Isolated.

FUNCTIONAL DESCRIPTION



Block Diagram

Table 2 Speed Control Function

HI/LO	OUTPUT TRANSITION TIME
0	10uS (12.5 KBS data)
1	1.5uS (100KBS data)

Table 3 Transmit Data Function

TTLIN1	TTLIN0	429OUTA	429OUTB	NOTES
0	0	0V	0V	Null output
0	1	-5V	5V	Zero output
1	0	5V	-5V	One output
1	1	0V	0V	Null output

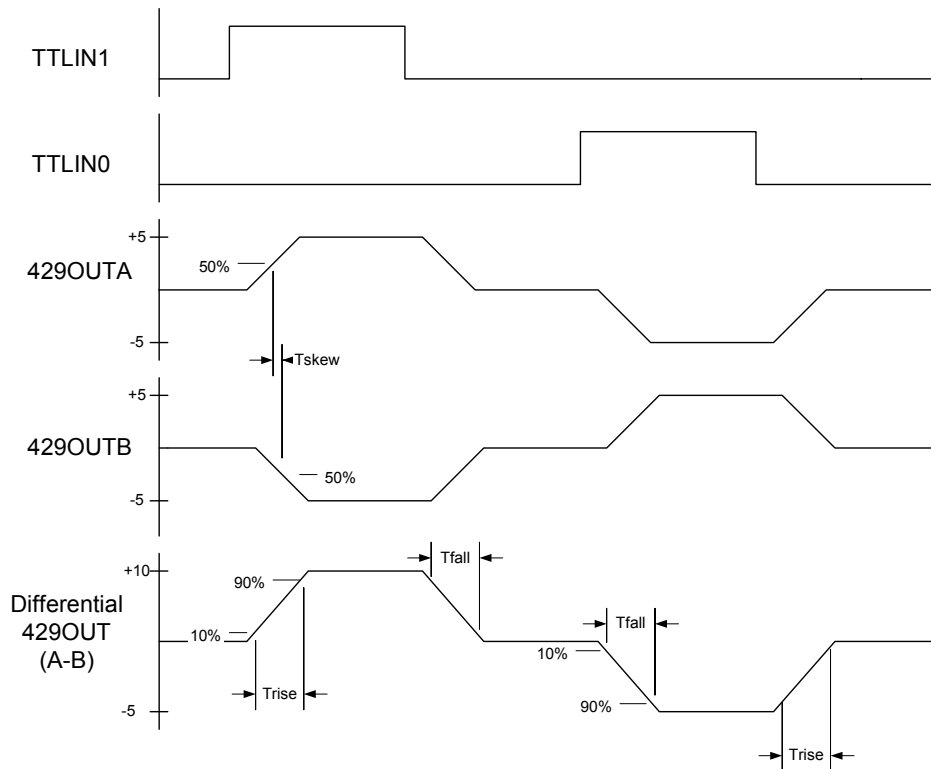


Figure 1 Timing Waveforms

ELECTRICAL DESCRIPTION

Table 4 Absolute Maximum Ratings

PARAMETER	MIN	MAX	UNITS
Voltages referenced to Ground			
V+ Supply Voltage	-0.3	+20	V
V- Supply Voltage	0.3	-20	V
V+, V- Supply Slew Rate		+/-100	V/uS
Storage Temperature	-65	+150	°C
Input Voltage TTLIN and HI/LO Inputs 429OUT Outputs	Gnd – 0.3 'V-' – 0.3	'V+' + 0.3 'V+' + 0.3	V V
Power Dissipation @ 85 °C: (> 10 Sec) 8 Lead EQ SOIC, thermal pad soldered to heat spreader land,		1.0	W
Junction Temperature: Tjmax, Plastic Packages (Limited by molding compound Tg) Tjmax, Ceramic Packages		145 160	°C °C
ESD per JEDEC A114-A Human Body Model		2000	V
Lead Soldering Temperature (10 sec duration)		280	°C
Notes:			
1. Stresses above absolute maximum ratings may cause permanent damage to the device.			
2. The device is tolerant of one or both outputs shorted to Ground and of both outputs shorted together.			

Table 5 Recommended Operating Conditions

PARAMETER	SYMBOL	CONDITIONS
Supply Voltage	V+ V-	9.5 to 16.5V -9.5 to -16.5V
Operating Temperature Plastic Package Ceramic Packages	T _{OP}	-55 to +85°C or -55 to +125 °C

Table 6 Electrical Characteristics

Conditions: Tcase = rated operating temperature: -55°C / +85°C or -55°C / +125°C.
V+/- = +/-9.5 to +/-16.5V Unless otherwise noted.

PARAMETER	TEST CONDITION	SYMBOL	MIN	NOM	MAX	UNITS
LOGIC INPUTS						
Input Voltage, Logic 1		V _{IH}	2.0		V+	V
Input Voltage, Logic 0		V _{IL}	-0.3		0.8	V
Input Current, Logic 1	V _{IN} = 5.0V	I _{IH}	0		100	uA
Input Current, Logic 0	V _{IN} = 0.0V	I _{IL}	0		-100	uA
ARINC OUTPUTS						
ARINC Output Voltage (Differential)	Differential Output Voltage = 429OUTA – 429OUTB. No Load.	V _{DIF1}	9.0	10.0	11.0	V
One		V _{DIFnull}	-0.5	0	+0.5	V
Null		V _{DIF0}	-9.0	-10.0	-11.0	V
Zero						
ARINC Output Voltage (Single Ended)	Referenced to Ground No Load.	V _{OHI}	4.5	5.0	5.5	V
Hi		V _{Onull.}	-0.25	0	+0.25	V
Null		V _{OLO}	-5.5	-5.0	-4.5	V
Lo						
ARINC Output Short Circuit Current	Outputs shorted to Ground.	I _{SCLO} I _{SCHI}		130 -130		mA mA
Output Resistance: DEI1070 DEI1071 DEI1072	Room Temperature	R _{out}		37.5 10 0		Ohms Ohms Ohms
Output Slew Rate Hi Speed	HI/LO = 1 No Load 10% to 90% voltage amplitude of differential output.	T _{rise} T _{fall}	1.0		2.0	uS
Output Slew Rate Lo Speed	HI/LO = 0 No Load 10% to 90% voltage amplitude of differential output.	T _{rise} T _{fall}	5		15	uS
Output skew time between A and B outputs.	HI/LO = 1 Measured at 50% voltage amplitude of both outputs.	T _{skew}			200	nS
SUPPLY CURRENT						
Quiescent Operating Supply Current: IV+ IV-	V+ = 15V, V- = -15V HI/LO = 0 or 1 TTLIN0=TTLIN1= 0V No Load	I _{V+} I _{V-}	- -14.0	6.0 -6.0	14.0 -	mA mA

DESIGN CONSIDERATIONS

Transient Voltage Protection

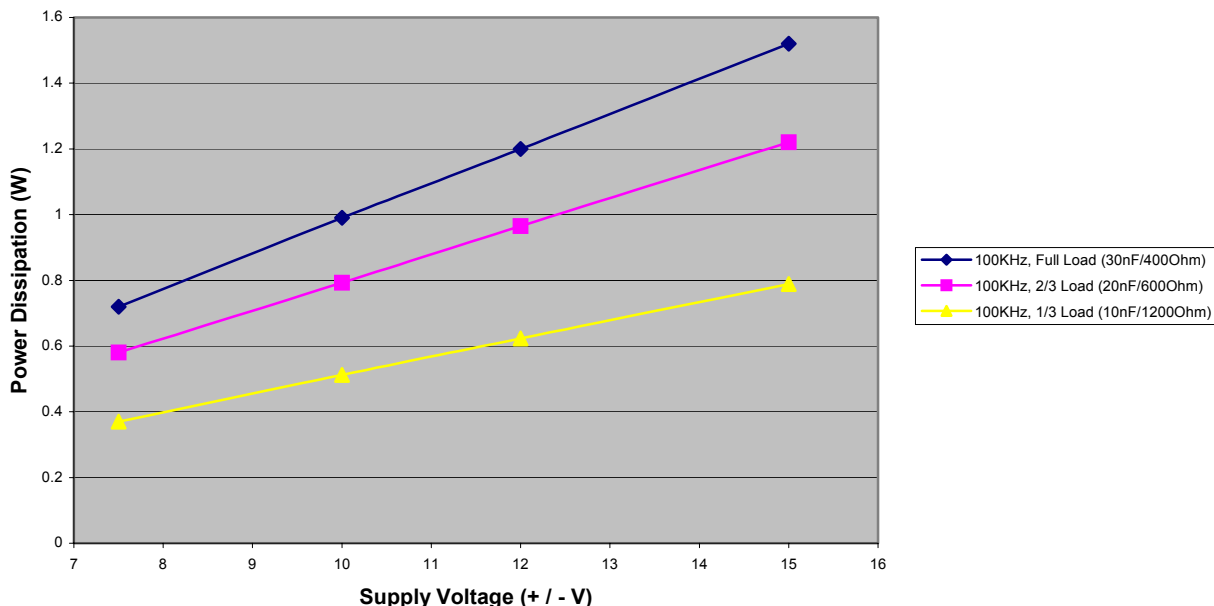
External transient voltage suppressing devices are required to protect the device from stress such as that defined by DO160D Section 22, Lightning Induced Transient Susceptibility. The output stage of the driver includes intrinsic clamp diodes to the V+ and V- power rails. Consider using the 0 Ohm output option to allow use of an external 36 Ohm current limiting resistor and transient voltage suppressor. Transients at the device must be limited to less than one diode drop beyond the power rails to prevent excessive current to the device.

Thermal Management

Device power dissipation varies greatly as a function of data rate, load capacitance, data duty cycle, and supply voltage. Proper thermal management is important in designs operating at the HI speed data rate (100KBS) with high capacitive loads and high data duty cycles. Dissipation may be estimated from the graph below which shows the approximate power dissipation for various loads and supply voltages. It is calculated for 100% data duty cycle at 100KBS with no word gap null times and must be reduced by the appropriate data duty cycle. Adjust for the application data duty cycle using a factor of (total bits transmitted in 10 sec period / 1,000,000) = (32 x total ARINC words transmitted in 10 sec period / 1,000,000).

Heat transfer from the IC package should be maximized. Use maximum trace width on all power and signal connections at the IC. The exposed heat sink pad of the SOIC package should be soldered to a heat spreader land on the PCB. The pad is electrically isolated. Maximize land size by extending beyond the IC outline if possible. Place vias on the signal/power traces close to the IC and on the heat spreader land to maximize heat flow to the internal power planes.

429 DRIVER DEVICE POWER DISSIPATION (100kbs, 100% DC)



PACKAGE DESCRIPTIONS

8 Lead EDQUAD SOIC

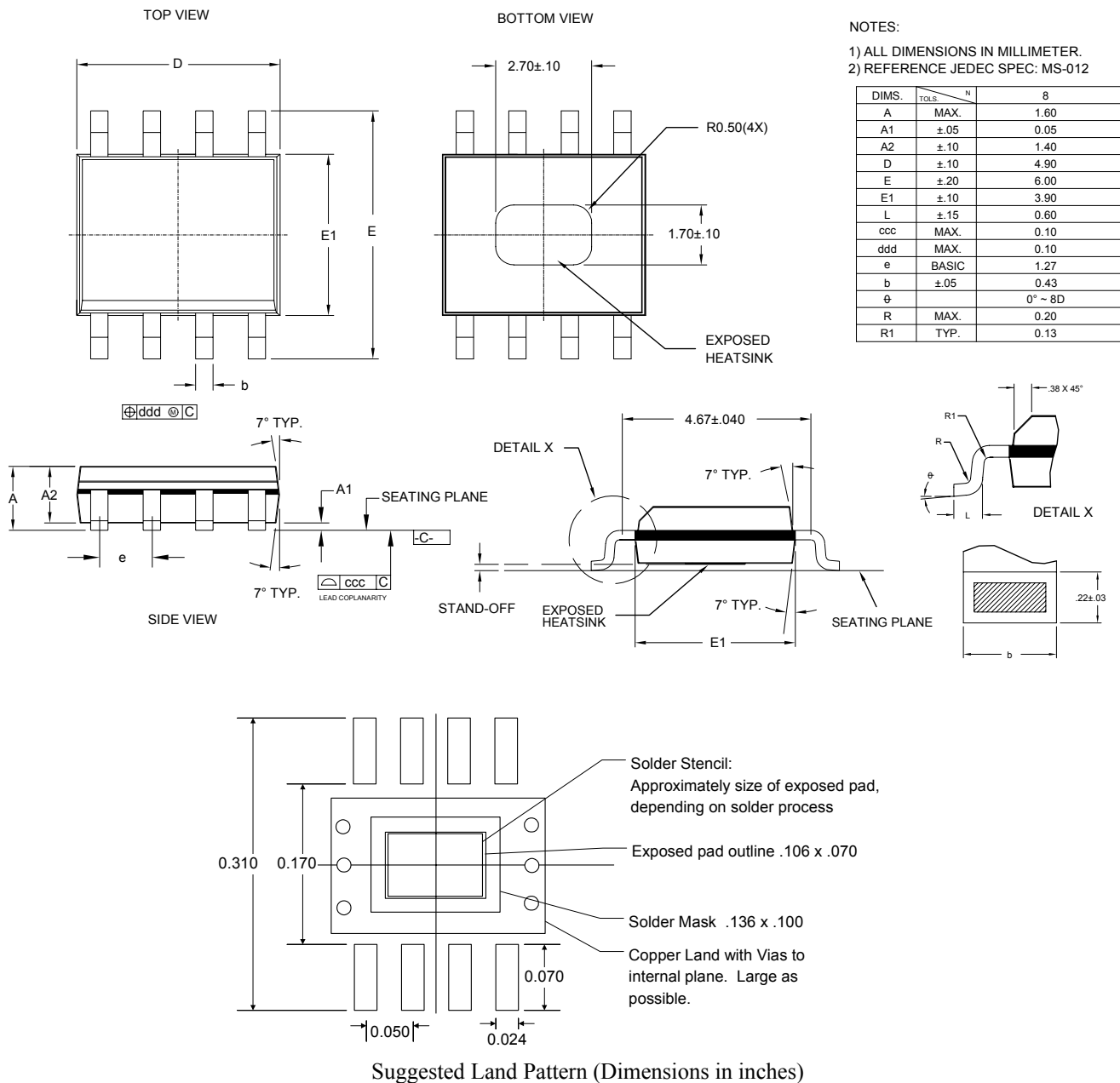


Table 7 8L EDQUAD SOIC Characteristics

SYMBOL	DESCRIPTION	VALUE	UNITS
Theta _{ja}	Junction to Ambient. 4 layer board with 2 internal power planes. Exposed pad soldered to .110" x .220" land with 6 vias.	59	°C/W
MSL	JEDEC Moisture Sensitivity Level Peak Body Temperature	2 235	- °C

8 Lead Ceramic Sidebrazed DIP

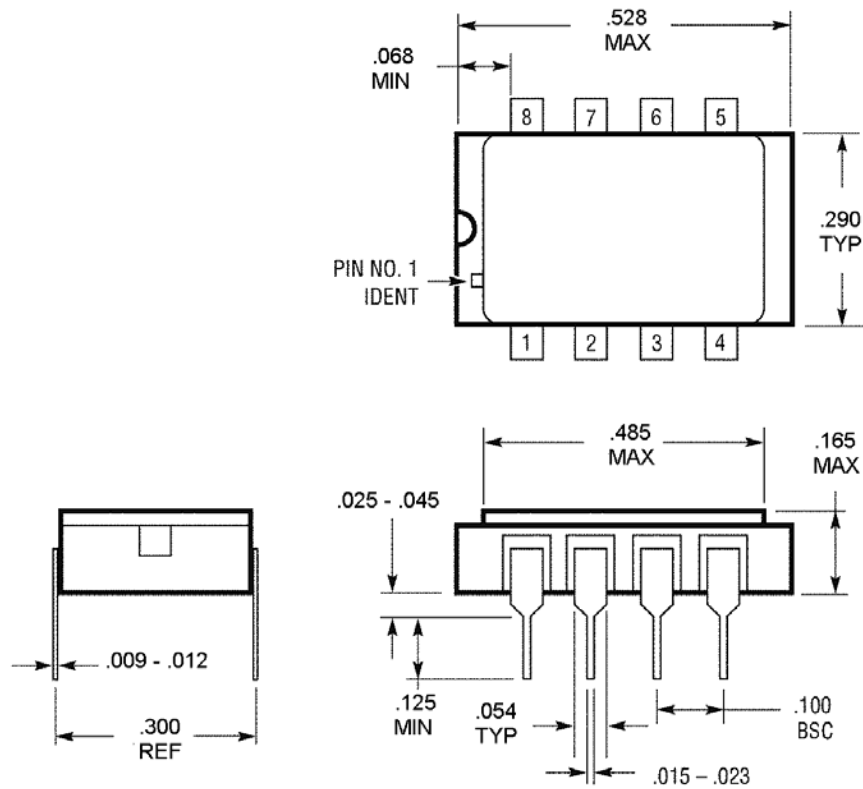


Table 8 8L SB DIP Characteristics

SYMBOL	DESCRIPTION	VALUE	UNITS
Theta _{jc}	Junction to Case	55	°C/W
Theta _{ja}	Junction to Ambient.	125	°C/W

PROCESS FLOW

Table 9 Process Flow

PROCESS STEP	STANDARD	BURN-IN
PRE-BURN-IN Electrical Test	N/A	YES
BURN IN (1)	N/A	96hrs @ +125 °C
FINAL ELECTRICAL TEST, Room Temperature	100%	100%
FINAL ELECTRICAL TEST, High Temperature	100% @ +85 or +125°C	100% @ +85 or +125°C
FINAL ELECTRICAL TEST, Low Temperature	0.65% AQL @ -55°C	0.65% AQL @ -55°C

NOTES:

1. Burn-in conditions: 125°C, 96 hrs, V+/V- = +/-15.0V Inputs = 0V, Outputs open.

ORDERING INFORMATION

Table 10 Ordering Information

Part Number	Marking	Package	Output Resistor	Burn-In	Temperature
DEI1070-SES	DEI1070 / SES	8L EQ SOIC	37	No	-55 / +85 °C
DEI1071-SES	DEI1071 / SES	8L EQ SOIC	10	No	-55 / +85 °C
DEI1072-SES	DEI1072 / SES	8L EQ SOIC	0	No	-55 / +85 °C
DEI1070-SMB	DEI1070 / SMB	8L EQ SOIC	37	Yes	-55 / +125 °C
DEI1071-SMB	DEI1071 / SMB	8L EQ SOIC	10	Yes	-55 / +125 °C
DEI1072-SMB	DEI1072 / SMB	8L EQ SOIC	0	Yes	-55 / +125 °C
DEI1070-DMS	DEI1070 / DMS	8L SB DIP	37	No	-55 / +125 °C
DEI1071-DMS	DEI1071 / DMS	8L SB DIP	10	No	-55 / +125 °C
DEI1072-DMS	DEI1072 / DMS	8L SB DIP	0	No	-55 / +125 °C
DEI1070-DMB	DEI1070 / DMB	8L SB DIP	37	Yes	-55 / +125 °C
DEI1071-DMB	DEI1071 / DMB	8L SB DIP	10	Yes	-55 / +125 °C
DEI1072-DMB	DEI1072 / DMB	8L SB DIP	0	Yes	-55 / +125 °C
DEI1070-SMS	DEI1070 / SMS	8L EQ SOIC	37	No	-55 / +125 °C
DEI1071-SMS	DEI1071 / SMS	8L EQ SOIC	10	No	-55 / +125 °C
DEI1072-SMS	DEI1072 / SMS	8L EQ SOIC	0	No	-55 / +125 °C

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